

Devices Connected/Referenced

ADF4350	Fractional-N PLL IC with Integrated VCO
ADP150	Low Noise 3.3 V LDO

Powering a Fractional-N Voltage Controlled Oscillator (VCO) with Low Noise LDO Regulators for Reduced Phase Noise

EVALUATION AND DESIGN SUPPORT

Circuit Evaluation Boards

[ADF4350 Evaluation Board \(EVAL-ADF4350-EB1Z\)](#)

Design and Integration Files

[Schematics](#), [Layout Files](#), [Bill of Materials](#)

CIRCUIT FUNCTION AND BENEFITS

This circuit uses low noise, low dropout (LDO) linear regulators to supply power to a wideband integrated PLL and VCO.

Wideband voltage controlled oscillators (VCOs) may have increased sensitivity to power supply noise, hence, ultralow noise regulators are recommended for best performance.

The circuit shown in Figure 1 utilizes the [ADF4350](#), a fully integrated fractional-N PLL and VCO that can generate frequencies from 137.5 MHz to 4400 MHz. The [ADF4350](#) is powered from the ultralow noise 3.3 V [ADP150](#) regulator for optimal LO phase noise performance.

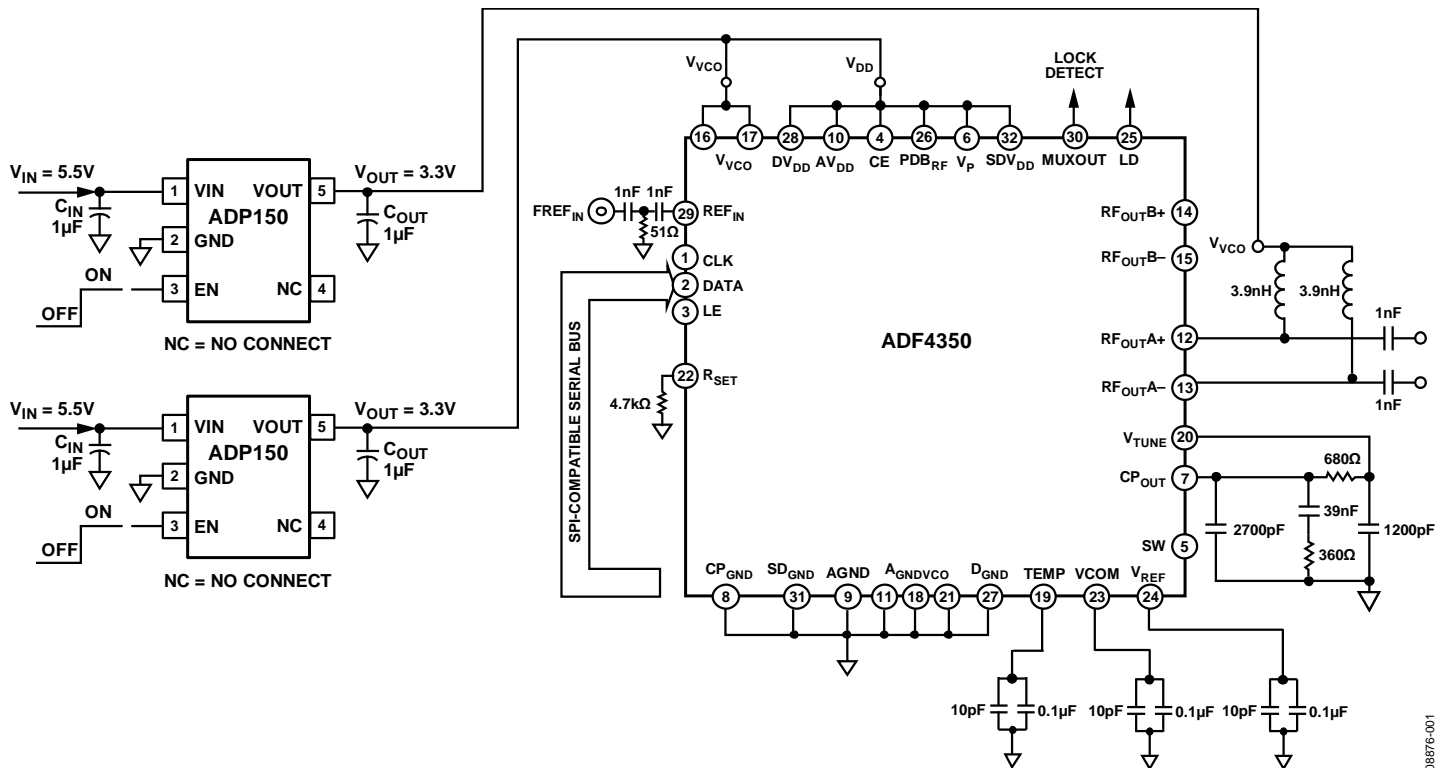


Figure 1. ADP150 Regulators Connected to ADF4350 (Simplified Schematic: All Connections and Decoupling Not Shown)

Rev. C

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Figure 2. EVAL-ADF4350EB1Z Rev. B Evaluation Board Featuring ADP150 Low Noise Regulators

The lower integrated rms noise of the [ADP150](#) LDO of only 9 μV rms (10 Hz to 100 kHz) helps to minimize VCO phase noise and reduce the impact of VCO *pushing* (the VCO equivalent of power supply rejection).

Figure 2 shows a photo of the evaluation board, which uses the [ADP150](#) LDOs to power the [ADF4350](#). The [ADP150](#) represents the industry's lowest noise LDO in the smallest package at the lowest cost. It is available in a 4-ball, 0.8 mm × 0.8 mm, 0.4 mm pitch WLCSP or a convenient 5-lead TSOT package. Adding the [ADP150](#)'s to the design, therefore, has minimal impact on system cost and board area while providing a significant improvement in phase noise.

CIRCUIT DESCRIPTION

The [ADF4350](#) is a wideband PLL and VCO consisting of three separate multiband VCOs. Each VCO covers a range of approximately 700 MHz (with some overlap between VCOs). Lower frequencies are generated by output dividers.

VCO *pushing* is measured by applying a steady dc tuning voltage to the [ADF4350](#) V_{TUNE} pin, varying the power supply voltage, and measuring the frequency change. The pushing figure (*P*) equals the frequency delta divided by the voltage delta, as shown in Table 1.

In a PLL system, higher VCO pushing means that power supply noise will degrade the VCO phase noise. If VCO pushing is low, then power supply noise will not significantly degrade phase noise. However, for high VCO pushing, noisy power supplies will have a measurable impact on phase noise performance.

Table 1. ADF4350 VCO Pushing

VCO Frequency (MHz)	V _{TUNE} (V)	VCO Pushing (MHz/V)
2200	2.5	0.73
3300	2.5	1.79
4400	2.5	5.99

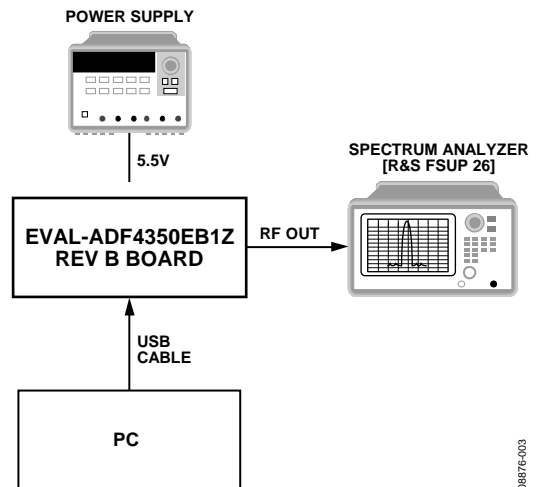


Figure 3. ADF4350 Measurement Setup

Experiments showed pushing to be at its maximum at 4.4 GHz VCO output frequency, so the comparison of VCO performance with different regulators was made at this frequency. Rev. A evaluation boards of the [ADF4350](#) used the [ADP3334](#) LDO regulator. The integrated rms noise of this regulator is 27 μV (integrated from 10 Hz to 100 kHz). This compares to 9 μV for the [ADP150](#), which is used on the EVAL-ADF4350EB1Z, Rev B. In order to measure the impact of the power supply noise, a narrow PLL loop bandwidth (10 kHz) was used to facilitate greater examination of VCO phase noise. A diagram of this setup is shown in Figure 3. A more detailed examination of the output noise density with frequency is available from the data sheets of both the [ADP3334](#) and [ADP150](#).

Figure 4 shows that the noise spectral density of the [ADP3334](#) regulator is 150 nV/√Hz at 100 kHz offset. The same plot for the [ADP150](#) (Figure 5) shows 25 nV/√Hz.

The formula for calculating the degradation in phase noise due to the power supply noise is as follows:

$$L_{(LDO)} = 20 \log \left(\frac{P \times S_{fm}}{\sqrt{2} \times fm} \right)$$

Where $L_{(LDO)}$ is the noise contribution from the regulator to the VCO phase noise (in dBc/Hz), at an offset fm ; P is the VCO pushing figure in Hz/V; S_{fm} is the noise spectral density at a given frequency offset in V/√Hz; and fm is the frequency offset at which the noise spectral density is measured in Hz.

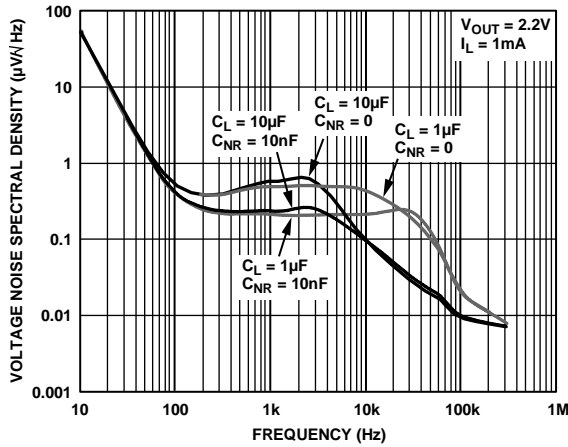


Figure 4. ADP3334 Output Noise Spectrum

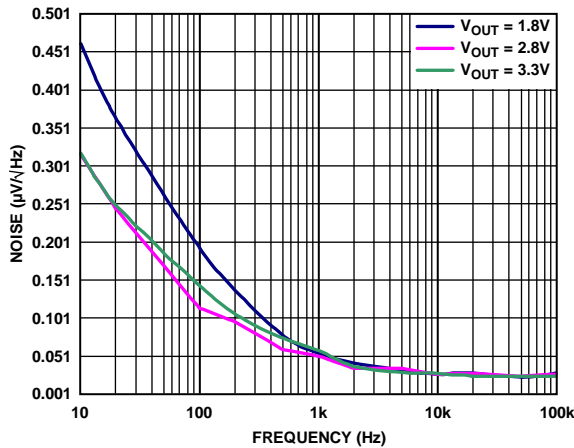


Figure 5. ADP150 output noise spectrum

The noise contribution from the supply is then rss summed with the noise contribution of the VCO (itself measured with a very low noise supply) to give the total noise at the VCO output with a given regulator.

These noise performances are rss summed together to give the expected VCO phase noise:

$$L_{(TOTAL)} = \sqrt{L_{(VCO)}^2 + L_{(LDO)}^2}$$

Or expressed in dB

$$L_{(TOTAL)} = 10 \log \left[\left(10^{L_{VCO}/20} \right)^2 + \left(10^{L_{LDO}/20} \right)^2 \right]$$

In this example, a 100 kHz noise spectral density offset is chosen, a 6 MHz/V pushing figure is used, and -110 dBc/Hz is taken as the VCO noise with an ideal supply.

Using a dedicated signal source analyzer (like Rohde & Schwarz FSUP), the VCO phase noise is compared. At 100 kHz offset the ADP3334 delivers -102.6 dBc/Hz (Figure 6), and in the same configuration the ADP150 measures -108.5 dBc/Hz (Figure 7).

Table 2. Calculation and Measurement of VCO Noise

	ADP3334	ADP150
Noise contribution from regulator (nV/√Hz)	150	25
Noise contribution from regulator (dBc/Hz)	-104	-119.5
Total calculated noise at VCO output (dBc/Hz)	-103	-109.5
Measured VCO noise at 100 kHz offset (dBc/Hz)	-102.6	-108.5

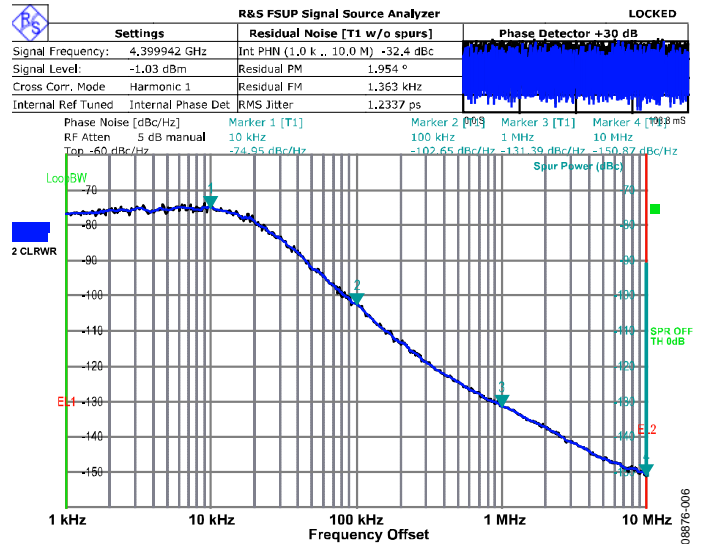


Figure 6. ADF4350 Phase Noise at 4.4 GHz with ADP3334 Regulators

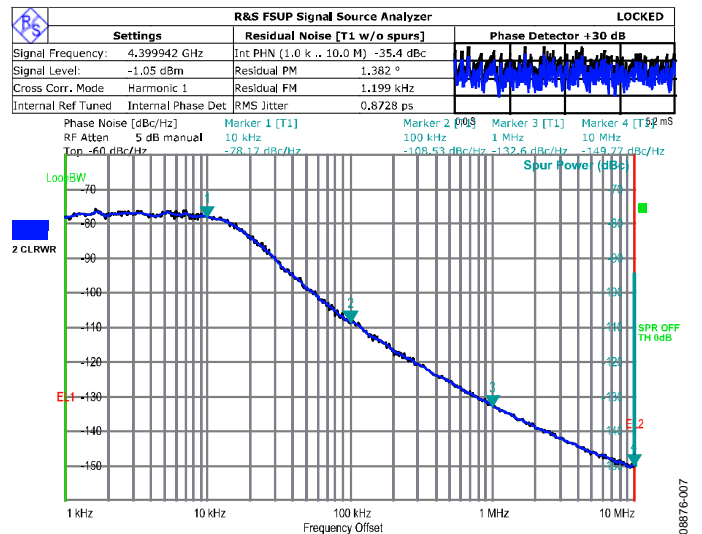


Figure 7. ADF4350 Phase Noise at 4.4 GHz with ADP150 Regulators

The integrated phase noise improves from 1.95° to 1.4° rms also. The measured results correlate very closely with the calculations and clearly show the benefit of using the ADP150 with the ADF4350.

A complete design support package for this circuit note can be found at <http://www.analog.com/CN0147-DesignSupport>.

COMMON VARIATIONS

Additional regulators can be added for greater isolation between power supplies, if desired. Also, one ADP150 regulator can be used to power the entire ADF4350 part. However, care needs to be taken in this case to ensure the maximum rated current of the single ADP150 regulator is not exceeded. This is possible if the lowest output power setting on the ADF4350 is selected.

CIRCUIT EVALUATION AND TEST

This circuit note, CN-0147, uses the EVAL-ADF4350EB1Z board for evaluation of the described circuit, allowing for quick setup and evaluation. The EVAL-ADF4350EB1Z board uses the standard ADF4350 programming software, contained on the CD that accompanies the evaluation board.

Equipment Needed

Windows® XP, Windows, Vista (32-bit), or Windows 7 (32-bit) PC with USB Port, the EVAL-ADF4350EB1Z, the ADF4350 programming software, 5.5 V power supply, and a spectrum analyzer such as a Rhode and Schwartz FSUP26. See this circuit note CN-0147 and UG-109 user guide for evaluation board EVAL-ADF4350EB1Z and the ADF4350 data sheet.

Getting Started

This circuit note, CN-0147, contains a description of the circuit, the schematic, and a block diagram of the test setup. The ser guide, UG-109, details the installation and use of the EVAL-ADF4350 evaluation software. UG-109 also contains board setup instructions and the board schematic, layout, and bill of materials.

Functional Block Diagram

This circuit note, CN-0147, contains the function block diagram of the described test setup in Figure 3.

Setup and Test

After setting up the equipment, standard RF test methods should be used to measure the spectral purity of the output signal.

LEARN MORE

CN0147 Design Support Package:

<http://www.analog.com/CN0147-DesignSupport>

[ADIsimPLL Design Tool](#)

[ADIsimPower Design Tool](#)

Basso, C., C. Fournet, and P. Kadanka. "Get the Best from Your Low-Dropout Regulator." *EDN*, 18 Feb. 1999.

Data Sheets and Evaluation Boards

[ADF4350 Data Sheet](#)

[ADF4350 Evaluation Board](#)

[ADP150 Data Sheet](#)

[ADP3334 Data Sheet](#)

REVISION HISTORY

6/11—Rev. B to Rev. C

Changes to Circuit Description2

11/10—Rev. A to Rev. B

Added Evaluation and Design Support Section1

Added Circuit Evaluation and Test Section4

7/10—Rev. 0 to Rev. A

Changes to Figure 11

Changes to Figure 32

4/10—Revision 0: Initial Version

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